



STALLMAN & POLLOCK LLP
121 Spear Street, Suite 290
San Francisco, CA 94105
(415) 512-1312

In re Patent Application of: Jeffrey T. Fanton et al.

Atty Docket No. TWI-13310

Application No.: 10/053,373

Filed: October 24, 2001

For: X-RAY REFLECTANCE MEASUREMENT SYSTEM WITH ADJUSTABLE RESOLUTION

M/S NON-FEE AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Transmittal herewith is an amendment in the above-identified application.

The fee has been calculated as shown below.

	CLAIMS REMAINING AFTER AMENDMENT		HIGHEST NO. PREVIOUSLY PAID FOR	PRESENT EXTRA	RATE	ADDITIONAL FEE
TOTAL	33	MINUS	33	0	x \$18 =	\$0
INDEP.	8	MINUS	8	0	x \$86 =	\$0
FIRST PRESENTATION OF MULTIPLE DEP CLAIMS						+ \$290
						TOTAL \$0

Small Entity 50% Filing Fee Reduction (if applicable)

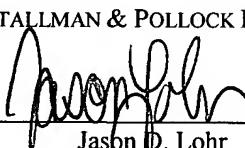
\$0

* If the entry in Col. 1 is less than the entry in Col. 2, write "0" in Col. 3
 ** If the "Highest Number Previously Paid For" IN THIS SPACE is less than 20, write "20" in this space.
 *** If the "Highest Number Previously Paid For" IN THIS SPACE is less than 3, write "3" in this space. The "Highest Number Previously Paid For" (Total or Independent is the highest number found from the equivalent box in Col. 1 of a prior amendment or the number of claims originally filed.)

1. No additional fee is required.
2. Enclosed for filing in the above-identified case an Associate Power of Attorney.
3. Please charge any additional fees, including any fees necessary for extensions of time or credit overpayment to Deposit Account No. 50-1703, under Order No. TWI-13310.
A duplicate copy of this sheet is enclosed.
4. Petition for extension of time. The undersigned attorney of record hereby petitions for an extension of time pursuant to 37 C.F.R. § 1.136(a), as may be required, to file this response.

STALLMAN & POLLOCK LLP

Dated: October 1, 2003

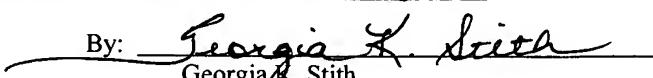
By: 

Jason D. Lohr (Reg. No. 48,163)
Attorneys for Applicant(s)

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on October 2, 2003.

Dated: October 2, 2003

By: 
Georgia K. Stith

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10/053,373

PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Jeffrey T. Fanton et al.

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Commissioner for Patents
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Alexandria, VA 22313-1450

Group Art Unit: 2882

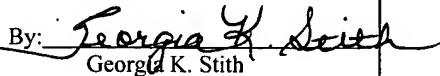
Examiner: I. Kiknadze

**RESPONSE TO OFFICE ACTION
MAILED JULY 18, 2003**121 Spear Street, Suite 290
San Francisco, CA 94105
(415) 512-1312**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope, addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on Oct. 2, 2003.

STALLMAN & POLLOCK LLP

Dated: 10/2/2003

By: 
Georgia K. Stith

Sir:

In response to the Office Action mailed July 18, 2003, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 10 of this paper.

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